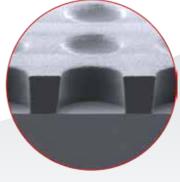


MLA150

The Advanced Maskless Aligner









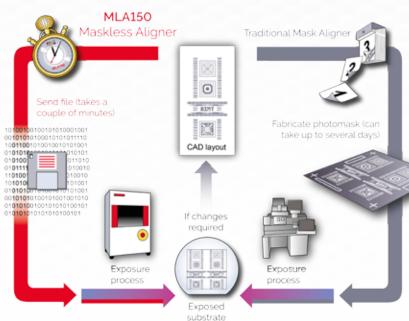
www.himt.de



MLA150

THE MASKLESS ALIGNER

The Maskless Aligner MLA150 takes you into the future of photolithography: The traditional photomask becomes a thing of the past as your design file is exposed directly onto the resist-coated wafer via a 2-dimensional Spatial Light Modulator.



In addition to flexibility and economy, MLA150 provides non-contact exposure, outstanding ease of use, and high speed, making it the ideal tool in rapid prototyping environments, for low- to mid-volume production, and Research & Development.

The Maskless Aligner was first introduced in 2015. Since then, the revolutionary, state-of-theart maskless technology has become firmly established. Today, the MLA150 serves as a trusted, indispensable workhorse in many multi-user facilities, nanofabrication labs, and national institutes. Application areas include MEMS, micro-optics, diffractive optical elements, sensors, electronic components and many more.

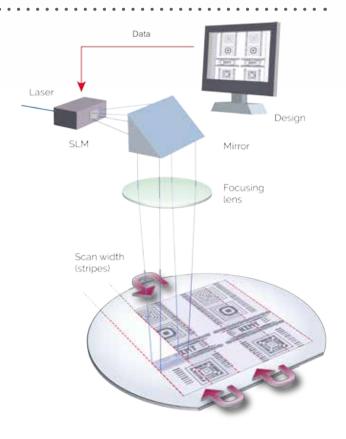
SPEED

- · High-speed Spatial Light Modulator (SLM)
- · Bidirectional writing process
- "Empty stripes" optimization
- Ultra-fast x-y stage

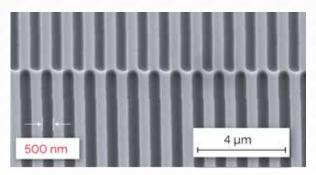
MLA150 exposure times ★

| Laser wavelength | 405 nm |
|---------------------------|------------|
| 50 x 50 mm ² | 4 minutes |
| 100 x 100 mm ² | 9 minutes |
| 150 x 150 mm ² | 16 minutes |
| 200 x 200 mm ² | 36 minutes |

 \bigstar For exposure at 100 mJ/cm² and minimum feature size of 1 μm

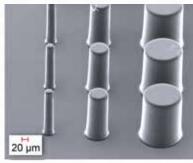


HIGH RESOLUTION



High-resolution mode: Vertical 500 nm lines and spaces. Resist: S1805. Wavelength: 375 nm

HIGH-ASPECT-RATIO

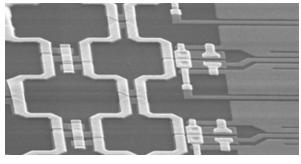


High-aspect ratio: Pillars. Resist: 160 µm SU-8

- Adjustable depth of focus
- Aspect ratio up to 1:20
- Applications: Micro-fluidics, MEMS, waveguides

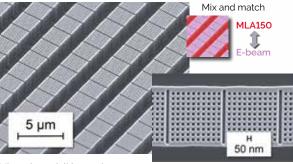
FAST AND HIGH-PRECISION ALIGNMENT

- Global and field-by-field alignment
- Backside alignment
- Alignment accuracy of better than 500 nm
- Fast and easy alignment procedure
- Alignment error compensation:
 Corrects for rotation, offset, scaling and shearing
- Allows mix and match between different tool sets, e.g. e-beam or thermal scanning probe lithography and laser lithography



SQUID magnetic flux sensor; 18 layer process

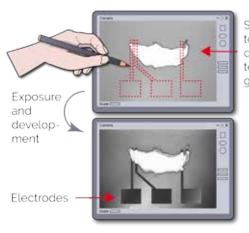
Courtesy of the Kirchhoff Institute for Physics, Heidelberg



Mix and match lithography

Courtesy of EPFL LMIS1, Lausanne

FLEXIBILITY



Structure to be connected, e.g. graphene

and 375 nm) make the system compatible with all broadband UV photoresists (including SU-8) and can both be installed in the MLA150 at the same time

The available solid state laser sources (405

- 3D-patterning with grayscale lithography
- Optional: exchangeable chucks with individual vacuum layouts
- The Draw Mode: Add individual features to a previously patterned substrate. Using graphic elements, or even a bitmap, simply "draw" the desired structures such as labels, markers, or electrical connections directly into the camera image

SYSTEM SPECIFICATIONS

| | Write Mode I ★ | Write Mode II ★ |
|--|---|-----------------|
| Writing performance | | |
| Minimum structure size [µm] | 0.6 | 1 |
| Linewidth variation [3σ, nm] | 100 | 120 |
| Global 2nd layer alignment [3σ, nm] | 500 | 500 |
| Local 2nd layer alignment [3σ, nm] | 250 | 250 |
| Backside alignment [3ơ, nm] | 1000 | 1000 |
| Exposure time 405 nm laser for 4" wafer [min] | 35 | 9 |
| Exposure time 375 nm laser for 4" wafer [min] | 35 | 20 |
| Max. write speed 405 nm laser [mm²/min] | 285 | 1100 |
| Max. write speed 375 nm laser [mm²/min] | 285 | 500 |
| System features | | |
| Light source | Diode lasers: 8 W at 405 nm, 2.8 W at 375 nm, or both | |
| Substrate sizes | Variable: $3 \times 3 \text{ mm}^2$ to $6'' \times 6'' \mid \text{Optional}$: $8'' \times 8''$ Customizable on request | |
| Substrate thickness | 0 - 12 mm | |
| Maximum exposure area | 150 x 150 mm² Optional: 200 x 200 mm² | |
| Temperature controlled flow box | Temperature stability ± 0.1° | |
| Real-time autofocus | Air-gauge or optical | |
| Autofocus compensation range | 180 μm | |
| Grayscale | 128 gray levels | |
| Software features | Exposure wizard, resist database, automatic labeling and serialization, Draw Mode for CADless exposures, substrate tracking / history | |
| System dimensions (lithography unit) | | |
| Height × width × depth | 1950 mm × 1300 mm × 1300 mm | |
| Weight | 1100 kg | |
| Installation requirements | | |
| Electrical | 230 VAC ± 5%, 50/60 Hz, 16 A | |
| Compressed air | 6 - 10 bar, stability ± 0.5 bar | |
| Economical considerations | | |
| Saves on the cost of photomasks | | |
| Low running costs for maintenance, energy consum | ption, spare parts | |

★ Only one write mode can be installed on the system

Please note: Specifications depend on individual process conditions and may vary according to equipment configuration. Write speed depends on exposure area. Design and specifications are subject to change without prior notice.

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